

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Carl W. Orthlieb, et al.                      Art Unit : 2131  
Serial No. : 10/080,923                                      Examiner : Christopher A. Revak  
Filed : February 21, 2002                                      Conf. No. : 7784  
Title : APPLICATION RIGHTS ENABLING

**MAIL STOP AMENDMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request. A copy of a communication from a foreign patent office in a counterpart application is also enclosed.

This statement is being filed before the receipt of a first Office Action after the filing of a Request for Continued Examination under 37 C.F.R. §1.114. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: October 16, 2006

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07844-518001	Application No. 10/080,923
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))		Applicant Carl W. Orthlieb, et al.	
		Filing Date February 21, 2002	Group Art Unit 2131

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AA	00/54128	09/14/2000	PCT				
	AB	01/61508	08/23/2001	PCT				

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AC	Ortiz, S "Email Protection Advances with New Technologies", Computer IEEE Service Center, Los Alamitos, CA, vol. 33, no. 1, XP000951701; ISSN: 0018-9162, , pages 21-23, January 2000.
	AD	
	AE	
	AF	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	